

RoHS

COMPLIANT

4405GM-VB Datasheet P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^d	Q _g (Typ.)			
- 30	0.011 at V _{GS} = - 10 V	- 13.5	29.5 nC			
- 30	0.015 at V_{GS} = - 4.5 V	- 11.6	29.3110			

8 D

7

6 D

D

5 D

SO-8

Top View

S

S

S

G

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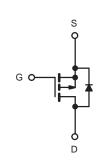
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FEATURES

- Halogen-free
- Trench Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Load Switch
- Notebook Adaptor Switch



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T	$A = 25 \ ^{\circ}C$, unless othe	erwise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 30	V	
Gate-Source Voltage	V _{GS}	± 20	v	
	T _C = 25 °C		- 13.5	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		- 11.9	
Continuous Drain Current $(T_j = 150^{\circ} C)$	T _A = 25 °C	I _D	- 10.9 ^{a, b}	
	T _A = 70 °C		- 8.6 ^{a, b}	•
Pulsed Drain Current	I _{DM}	- 50	Α	
	T _C = 25 °C	1	- 4.1	
Continuous Source-Drain Diode Current	T _A = 25 °C	Is –	- 2.2 ^{a, b}	
Avalanche Current	1 0.4 ml l	I _{AS}	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	20	mJ
	T _C = 25 °C		5.0	
Maximum Davian Disaination	T _C = 70 °C	Б	3.2	14/
Maximum Power Dissipation	T _A = 25 °C	P _D	2.7 ^{a, b}	W
	T _A = 70 °C	1	1.7 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	38	46	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	20	25	C/W	

Notes:

b. t = 10 s.

c. Maximum under Steady State conditions is 85 $^{\circ}\text{C/W}.$

d. Based on T_C = 25 °C.

a. Surface mounted on 1" x 1" FR4 board.



SPECIFICATIONS T _J = 25 °C Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	Symbol	Test conditions	IVIIII.	тур.	Wax.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	VGS = 0 4, 10 = 200 p. 4	- 50	- 34		-	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		5.3		mV/ °C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = - 250 μA	- 1.4	5.5	- 2.5	V	
Gate-Source Leakage		$V_{DS} = 0 \text{ V}, \text{ V}_{GS} = \pm 25 \text{ V}$	- 1.4		± 100	nA	
Gale-Source Leakage	I _{GSS}	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = -23 \text{ V}$			± 100 - 1	ΠA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			- 1	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, \text{ V}_{GS} = -10 \text{ V}$	- 30			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 10 V, I _D = - 10 A		0.011		Ω	
	. ,	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -8 \text{ A}$		0.015			
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		28		S	
Dynamic ^b	-					1	
Input Capacitance	C _{iss}			2550		pF	
Output Capacitance	C _{oss}	$V_{DS} = -15 V$, $V_{GS} = 0 V$, f = 1 MHz		455			
Reverse Transfer Capacitance	C _{rss}			390			
Total Gate Charge	Q _g	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		57	86	_	
				29.5	45	nC	
Gate-Source Charge	Q _{gs}	V_{DS} = - 15 V, V_{GS} = - 4.5 V, I_D = - 10 A		8		-	
Gate-Drain Charge	Q _{gd}		0.5	22		0	
Gate Resistance	Rg	f = 1 MHz	0.5	2.2	4.4	Ω	
Turn-On Delay Time	t _{d(on)}			13	25	-	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_{L} = 1.5 \Omega$		12	24	-	
Turn-Off DelayTime	t _{d(off)}	$I_{D}\cong$ - 10 A, V_{GEN} = - 10 V, R_{g} = 1 Ω		40	70		
Fall Time	t _f			9	18	ns	
Turn-On Delay Time	t _{d(on)}			48	80		
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_{L} = 1.5 \Omega$		92	160		
Turn-Off DelayTime	t _{d(off)}	${\rm I}_{\rm D}$ \cong - 10 A, ${\rm V}_{\rm GEN}$ = - 4.5 V, ${\rm R}_{\rm g}$ = 1 Ω		34	60		
Fall Time	t _f			19	35		
Drain-Source Body Diode Characteris			[1		1	
Continous Source-Drain Diode Current	۱ _s	T _C = 25 °C			- 4.1	A	
Pulse Diode Forward Current	I _{SM}				- 60		
Body Diode Voltage	V _{SD}	I _S = - 3 A, V _{GS} = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			27	45	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 10 A, dl/dt = 100 A/μs, T _{.1} = 25 °C		16	27	nC	
Reverse Recovery Fall Time	t _a	F = 1000, 0000 = 10000000, 10 = 2000		12		ns	
Reverse Recovery Rise Time	t _b			15		115	

Notes:

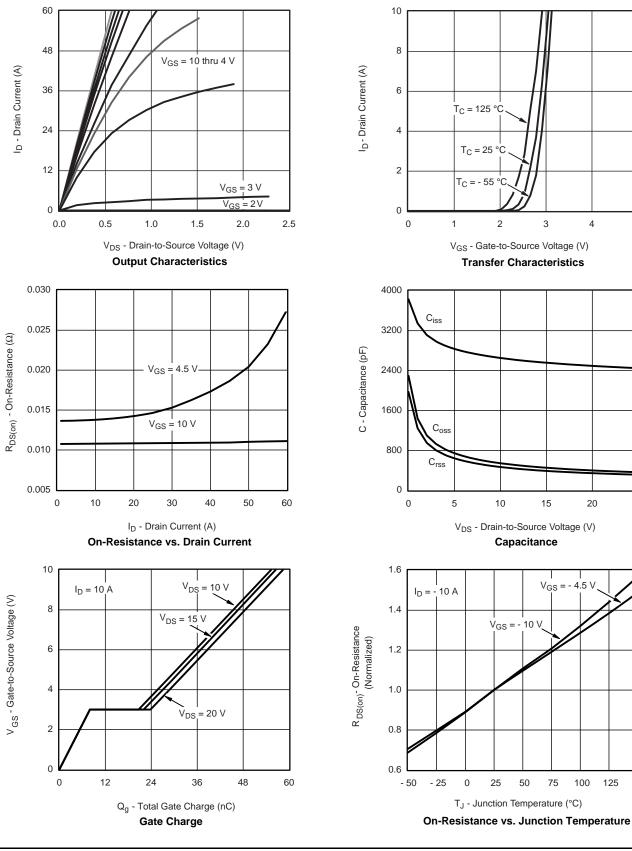
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



4.5



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



I_D = 10 A

T_J = 25 °C

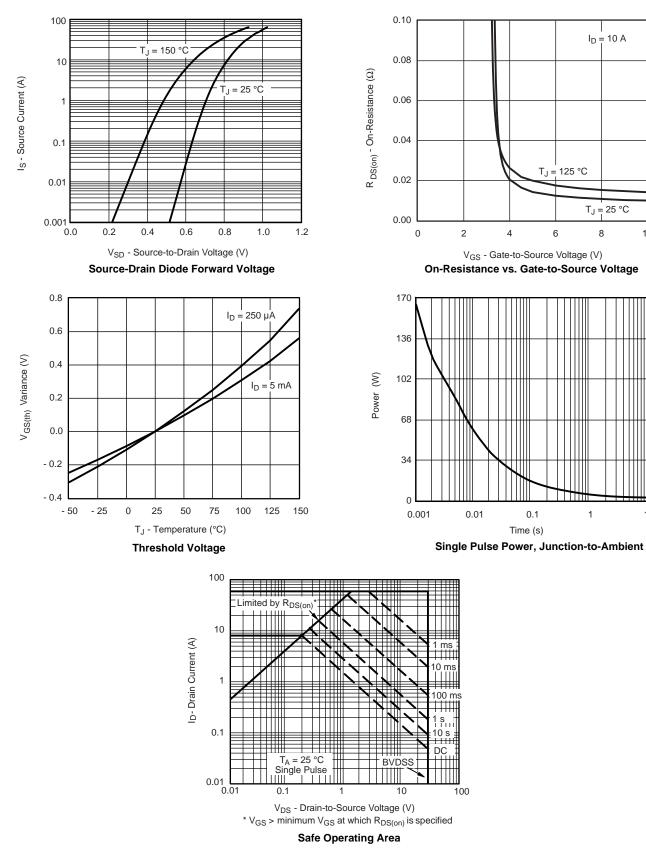
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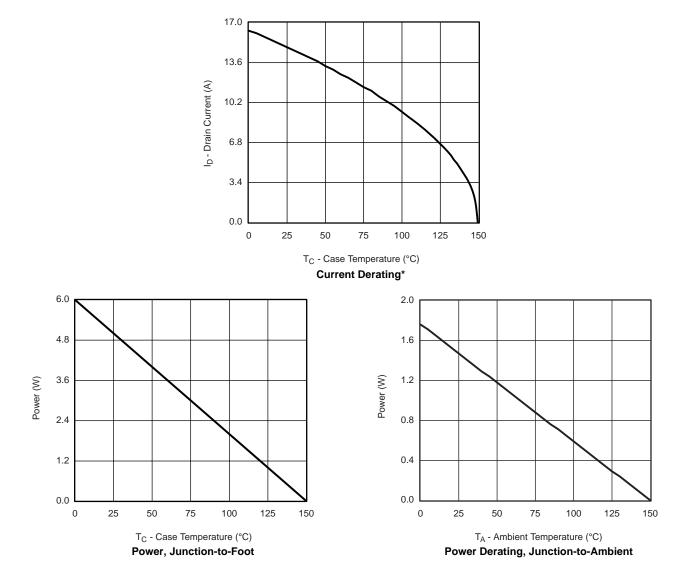
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



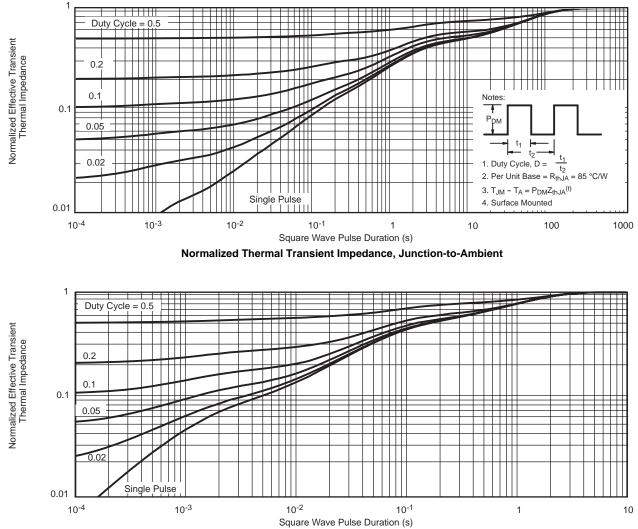
MOSFET TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.







Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

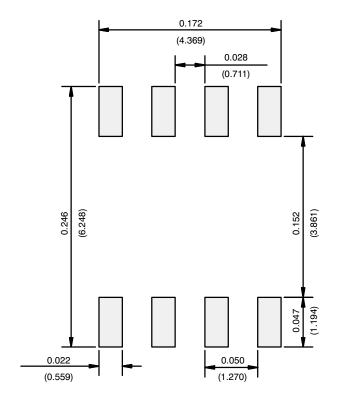




	MILLIM	IETERS	INC	HES		
DIM	Min	Мах	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050 BSC			
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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